Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/826,773	HARPER, JOHN	
Examiner	Art Unit	
CHAMELI C. DAS	2192	

	SEAR	CHED	
Class	Subclass	Date	Examiner
717	132,141, 144	4/12/06	CD
345	763		
715	763		
700	17	<i>y</i>	+
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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Search for double patenting WEST - USPATFILE - USPGPUB - US OCR - JPO ABS - EPO ABS - DWPI - IBM TECH	4/12/2006	CD		
ACM IEEE	4/12/2006	CD		
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